FORM PTO-1449 (Modified)

ATTY. DOCKET NO. 6487/60420

SERIAL NO. 09/894,568

LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT(S)' INFORMATION DISCLOSURE STATEMENT

APPLICANT: Kim, et al.

0 9 2002 ° 8/

(Use several sheets if necessary)

FILING DATE June 27, 2001 GROUP ART UNIT

2675

FERENCE DESIGNATION U.S. PATENT DOCUMENTS

REFERE.	NCE DE	SIGNATION U.	J. IAILIVI	DOCUMENTS		Т	<u> </u>
EXAM'R INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	Subclass	Filing Date If Appro- priate
CAN	A1	5,049,863	09/17/91	Oka			
XXXX) A2	5,063,289	11/05/91	Jasinski, et al.			
	A3	5,126,955	06/30/92	Tomoda			
DATA!	A4	5,231,381	07/21/93	Duwaer			
) A5	5,307,297	04/26/94	Iguchi, et al.			
DEM	A6	5,327,161	07/05/94	Logan, et al.			
	A7	5,428,368	06/27/95	Grant		RECE	IVED
NXIX	A8	5,457,479	10/10/95	Cheng		TILUE	IVED
ZAM	A9	5,459,489	10/17/95	Redford		JAN 1	6 2002
MXXII	A10	5,481,265	01/02/96	Russell		JAN I	2002
SULTIN	A11	5,490,039	02/06/96	Helms	To	chnology (enter 2600
	A12	5,546,334	08/13/96	Hsieh, et al.	10	cinology (- CIILGI 2000

REFERENCE DESIGNATION FOREIGN PATENT DOCUMENTS								
EXAM'R		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	Subclass	TRANSLAT'ION	
INITIAL							yes no	
()	B1	5-11922	01/22/93	Japan			yes (partial)	
	B2	6-19582	01/28/94	Japan			yes (partial)	
	В3	2-210523	08/20/93	Japan			yes (abstract only)	
CIDIL O	B4	3-63810	03/19/91	Japan			yes (partial)	
MIXED	B5	4-152417	05/26/92	Japan			yes	
	В6	7-261928	10/13/95	Japan			yes (partial)	
	B7	9-297630	11/18/97	Japan			yes (partial)	
	В8	1-178638	12/21/89	Japan		_	yes (partial)	
OND	\B9	2-58838	04/27/90	Japan			yes (partial)	
KKK	B10	62-169842	10/28/87	Japan			yes (partial)	
27117	<u> </u>		· · · · · ·					

EXAMINER DATE CONSIDERED DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant(s).

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REFERE	CE DE	ESIGNATION U.S	S. PATENT	DOCUMENTS_			
REFERE TRADEM'R EXAM'R INITIAL		DOCUMENT NÜMBER	DATE	NAME	CLASS	Subclass	Filing Date If Appro- priate
MAKE	A13	5,563,630	10/08/96	Tsakiris, et al.			
	A14	5,572,033	11/05/96	Grant			
02	A15	5,576,733	11/19/96	Lo			
(ZHZ)	A16	5,648,798	07/15/97	Hamling			
	A17	5,669,004	09/16/97	Sellers		REC	EIVED
CANA	A18	5,669,015	09/16/97	Chidester, et al.			
	A19	5,707,160	01/13/98	Bowen		JAN 1	6 2002
	A20	5,726,684	03/10/98	Blankenship, et al.			
ALL S	A21	5,754,126	05/19/98	Hilbrink, et al.		echnology	Center 2600
	A22	5,764,224	06/09/98	Lilja, et al.		3,	
	A23	5,659,335	08/19/97	Partridge, III			

REFERENCE DESIGNATION FOREIGN PATENT DOCUMENTS							
EXAM'R		DOCUMENT NUMBER	DATE	NAME	CLASS	Subclass	Filing Date If Appro- priate
AW)	B11	63-72640	05/16/88	Japan			yes (partial)
(010)	B12	2-210522	08/21/90	Japan			yes (abstract only)
SION	B13	5-197491	08/06/93	Japan			yes (partial)
CHON	B14	6-119113	04/28/94	Japan			yes (partial)
CON	B15	8-211998	08/20/96	Japan			yes (partial)
(NVI)	B16	9-69026	03/11/97	Japan			yes (partial)
JU	B17	10-187347	07/14/98	Japan			yes (partial)
UN	B18	10-198512	07/31/98	Japan			yes (partial)
ON IV	B19	EP 712066	05/15/96	Europe			yes

C1 C2 C3 C4 C5

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